

Model Error in the ECMWF Ensemble of Data Assimilations

Massimo Bonavita

ECMWF

Acknowledgments: Lars Isaksen, Martin Leutbecher

Outline

- Estimation of analysis and background error statistics with the Ensemble of Data Assimilations (EDA)
- Parameterizations of model error in the ECMWF EDA
- Impact of model error parameterizations on the EDA sample statistics
- Conclusions and Plans

The EDA method

For a linear system the data assimilation update is:

$$\begin{aligned}\mathbf{x}_a^k &= \mathbf{x}_b^k + \mathbf{K}_k (\mathbf{y}^k - \mathbf{H}_k \mathbf{x}_b^k) \\ \mathbf{x}_b^{k+1} &= \mathbf{M}_k \mathbf{x}_a^k\end{aligned}$$

Under the assumptions of statistically independent background (\mathbf{P}^b), observation (\mathbf{R}) and model errors (\mathbf{Q}), the evolution of the system error covariances is given by:

$$\begin{aligned}\mathbf{P}_k^a &= (\mathbf{I} - \mathbf{K}_k \mathbf{H}_k) \mathbf{P}_k^b (\mathbf{I} - \mathbf{K}_k \mathbf{H}_k)^T + \mathbf{K}_k \mathbf{R}_k \mathbf{K}_k^T \\ \mathbf{P}_{k+1}^b &= \mathbf{M}_k \mathbf{P}_k^a \mathbf{M}_k^T + \mathbf{Q}_k\end{aligned}$$

The EDA method

Consider now the evolution of the same system where we perturb the observations and the forecast state (t_{k+1}) with random noise drawn from the respective error covariances:

$$\begin{aligned}\tilde{\mathbf{x}}_a^k &= \tilde{\mathbf{x}}_b^k + \mathbf{K}_k (\mathbf{y}^k + \boldsymbol{\eta}_k - \mathbf{H}_k \mathbf{x}_b^k) \\ \mathbf{x}_b^{k+1} &= \mathbf{M}_k \mathbf{x}_a^k + \boldsymbol{\zeta}_k\end{aligned}$$

where $\boldsymbol{\eta}_k \sim \mathbf{N}(\mathbf{0}, \mathbf{R})$, $\boldsymbol{\zeta}_k \sim \mathbf{N}(\mathbf{0}, \mathbf{Q})$.

If we define the **differences between the perturbed and unperturbed state** $\boldsymbol{\varepsilon}_a \equiv \tilde{\mathbf{x}}_a - \mathbf{x}_a$ and $\boldsymbol{\varepsilon}_b \equiv \tilde{\mathbf{x}}_b - \mathbf{x}_b$, their evolution and the evolution of their sample statistics are governed by the same equations (Fisher et al., 2005):

$$\begin{aligned}\boldsymbol{\varepsilon}_a^k &= \boldsymbol{\varepsilon}_b^k + \mathbf{K}_k (\boldsymbol{\eta}_k - \mathbf{H}_k \boldsymbol{\varepsilon}_b^k) \\ \boldsymbol{\varepsilon}_b^{k+1} &= \mathbf{M}_k \boldsymbol{\varepsilon}_a^k + \boldsymbol{\zeta}_k\end{aligned}$$

The EDA method

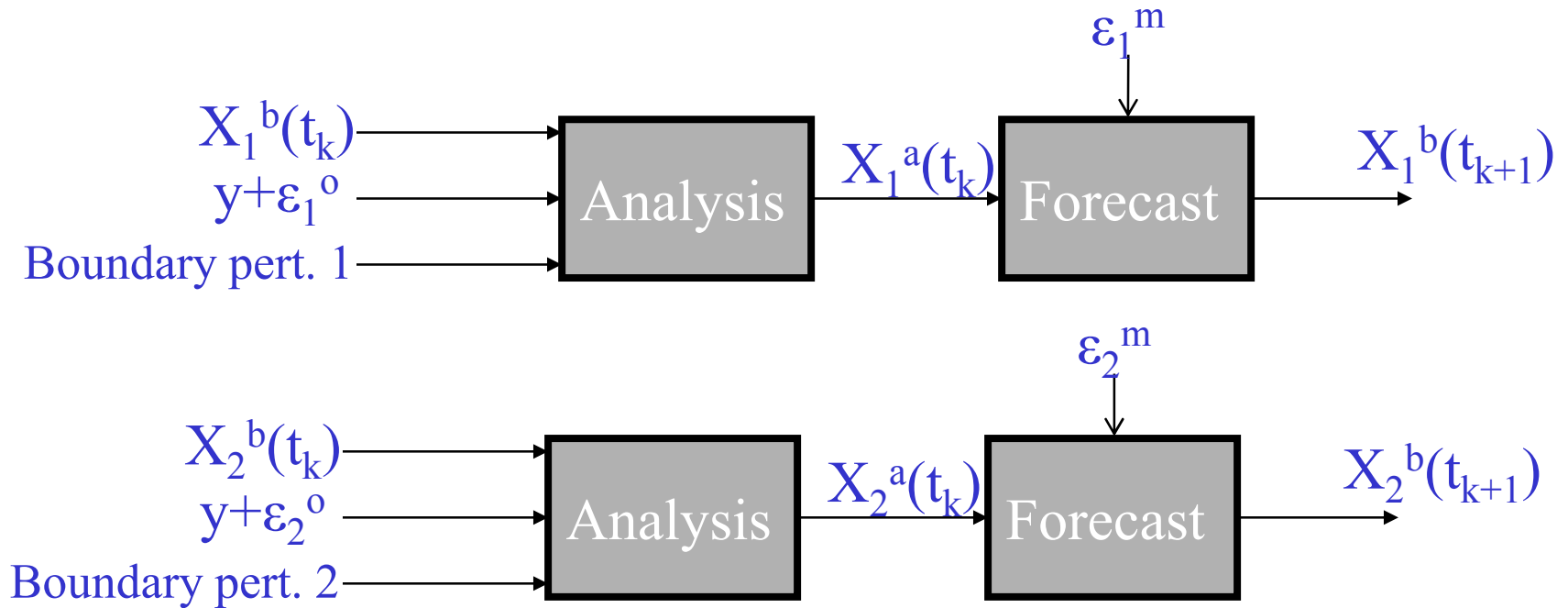
$$\left\langle \boldsymbol{\varepsilon}_k^a \left(\boldsymbol{\varepsilon}_k^a \right)^T \right\rangle = \left(\mathbf{I} - \mathbf{K}_k \mathbf{H}_k \right) \left\langle \boldsymbol{\varepsilon}_k^b \left(\boldsymbol{\varepsilon}_k^b \right)^T \right\rangle \left(\mathbf{I} - \mathbf{K}_k \mathbf{H}_k \right)^T + \mathbf{K}_k \mathbf{R}_k \mathbf{K}_k^T$$

$$\left\langle \boldsymbol{\varepsilon}_{k+1}^b \left(\boldsymbol{\varepsilon}_{k+1}^b \right)^T \right\rangle = \mathbf{M}_k \left\langle \boldsymbol{\varepsilon}_k^a \left(\boldsymbol{\varepsilon}_k^a \right)^T \right\rangle \mathbf{M}_k^T + \mathbf{Q}_k$$

This implies that:

1. We can use an ensemble of perturbed assimilation cycles to simulate the errors of our reference assimilation cycle;
2. The ensemble of perturbed DAs should be as similar as possible to the reference DA (i.e., same or similar \mathbf{K} matrix)
3. The applied perturbations $\boldsymbol{\eta}_k$, $\boldsymbol{\zeta}_k$ must have the required error covariances (\mathbf{R} , \mathbf{Q});

The EDA method



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The EDA method

- **10** ensemble members using 4D-Var assimilations
- **T399** outer loop, **T95/T159** inner loops. (Reference DA: **T1279** outer loop, **T159/T255/T255** inner loops)
- Perturbation applied to all relevant sources of uncertainty:
 1. **Observations** randomly perturbed according to their prescribed **R** matrix;
 2. **SST** perturbed with climatological error structures
 3. **Model error** represented by stochastic methods

Model error representation

- In the EDA we do not represent model error through a covariance matrix (Kalman filter – Weak constraint 4D-Var) but with physically plausible Monte Carlo realizations
- Two model error parameterizations are available in the IFS:
 1. Stochastically Perturbed Parameterization Tendencies (**SPPT**)
 2. Stochastic Kinetic Energy Backscatter (**SKEB**)
- They are both used in the operational Ensemble Prediction System (EPS)
- Only the SPPT parameterization is currently used in operational EDA
- Goal: Converge toward a **unified representation**

Model error representation

Stochastically Perturbed Parameterization Tendencies (SPPT)

- **Physics tendencies** P perturbed by $\Delta P = rP$, with r a random pattern
- Gaussian distribution, truncated at 2 (instead of uniform distr.)
- Same pattern r for T; q; u; v
- Random pattern r uses AR-1 processes in spectral space and is smooth in space and time
- Three components with different correlation scales: 6 h, 3 d, 30 d and 500 km, 1000 km, 2000 km
- Improved version of the original SPPT scheme (stochastic physics, Buizza, Miller & Palmer (1999))

Model error representation

Stochastic Kinetic Energy Backscatter (SKEB)

- Rationale: A fraction of the dissipated energy is backscattered upscale and acts as **streamfunction forcing** for the resolved-scale flow (Shutts and Palmer 2004, Shutts 2005, Berner et al. 2009)

$$\text{Streamfunction forcing} = [bD]^{1/2} F(x; t);$$

where b,D,F denote the backscatter ratio, the (smoothed) total dissipation rate and the 3-dim evolving pattern

- **Total dissipation rate**: sum of
 1. "Numerical" dissipation: loss of KE by numerical diffusion + interpolation in semi-Lagrangian advection;
 2. Dissipation from **orographic gravity wave drag** parameterization;
 3. An estimate of the deep convective KE production
- Boundary layer dissipation is omitted
- see Tech Memo 598, Palmer et al. (2009) for details

from: M. Leutbecher

Impact of model error parameterizations

- The impact of different model error parameterizations can be evaluated in the context of an EDA
- This is arguably a different and more stringent test than is possible with an EPS:
 1. Effects accumulate over assimilation cycles;
 2. Background errors for use in the deterministic analysis require the estimation of **multivariate** pdfs;
 3. Background errors span a larger portion of phase space than forecast errors at longer lead times

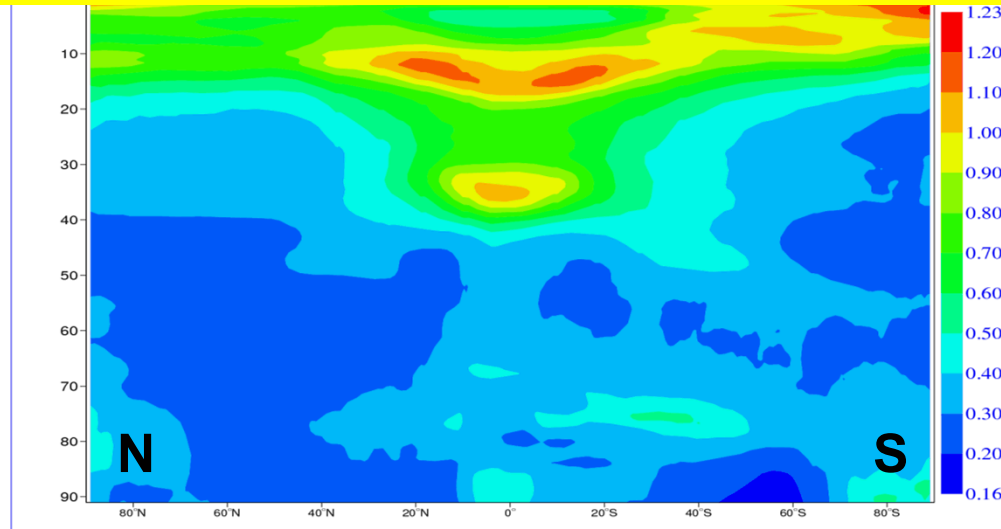
Impact of model error parameterizations

- To test these ideas three EDA cycles have been run with different model error parameterizations:
 1. **fgk7**: no model error parameterizations;
 2. **fi8s**: SPPT parameterization;
 3. **fgk6**: SPPT + SKEB parameterizations
- All other aspect of the EDA setup are equal
- Results shown are time averages over a 20 day period (i.e., 40 assimilation cycles; 20100405 – 20100425)

Impact of model error parameterizations

EDA Temperature spread – no model error (fgk7)

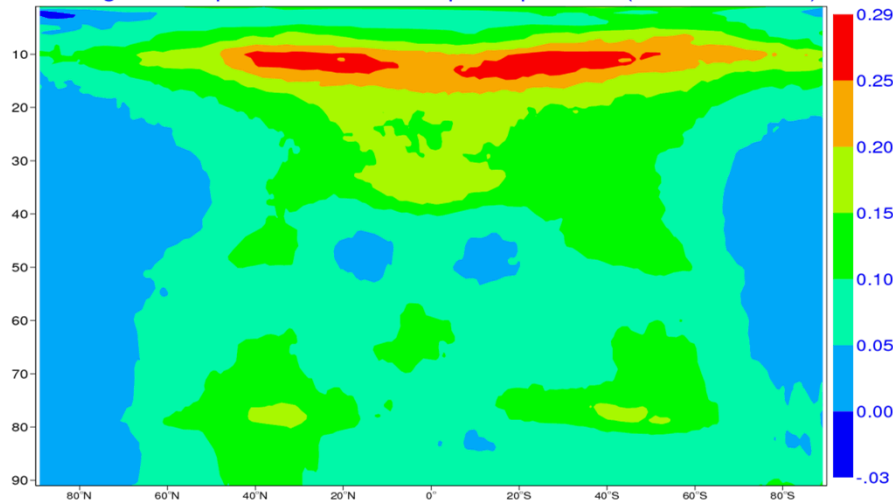
Mean Vertical
EDA T spread
Cross Section



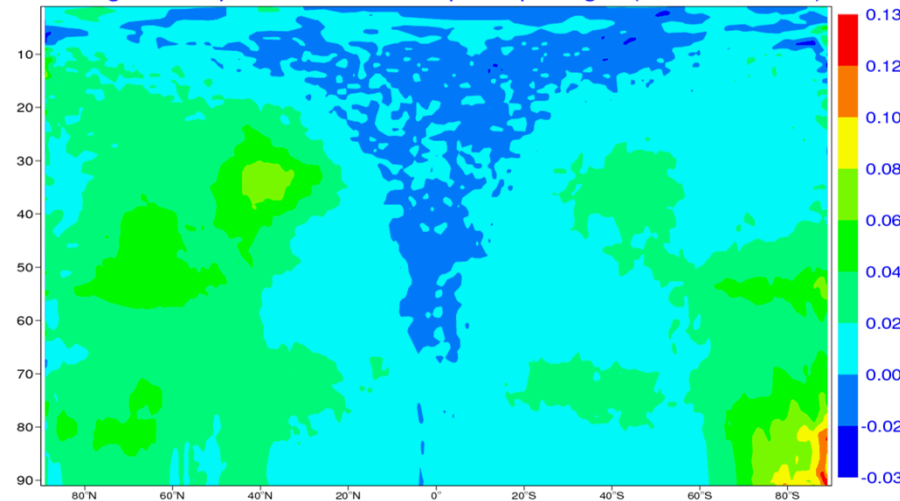
Impact of SPPT on T spread (fi8s-fgk7)

Addit. Impact of SKEB on T spread (fgk6-fi8s)

Average of temp 20100405 600 step 3 Expver fi8s (180.0W-180.0E)



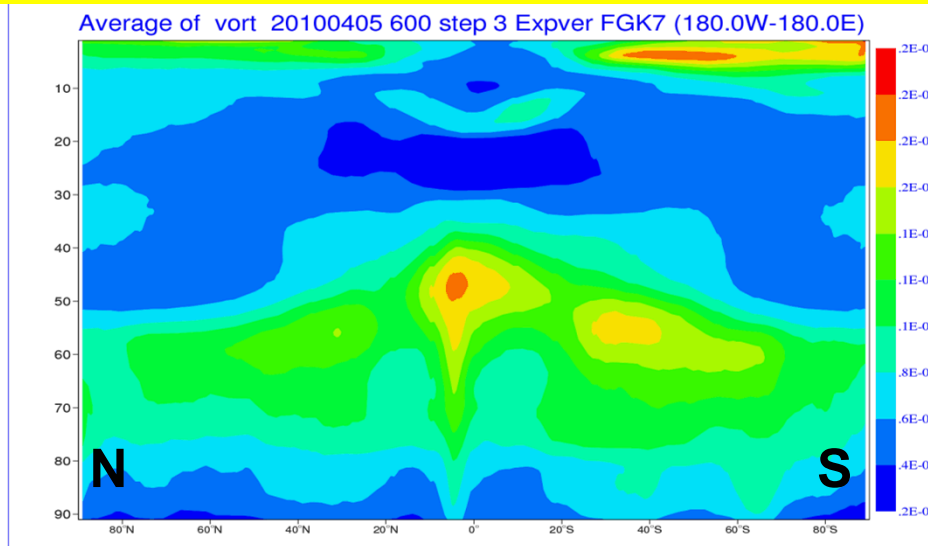
Average of temp 20100405 600 step 3 Expver fgk6 (180.0W-180.0E)



Impact of model error parameterizations

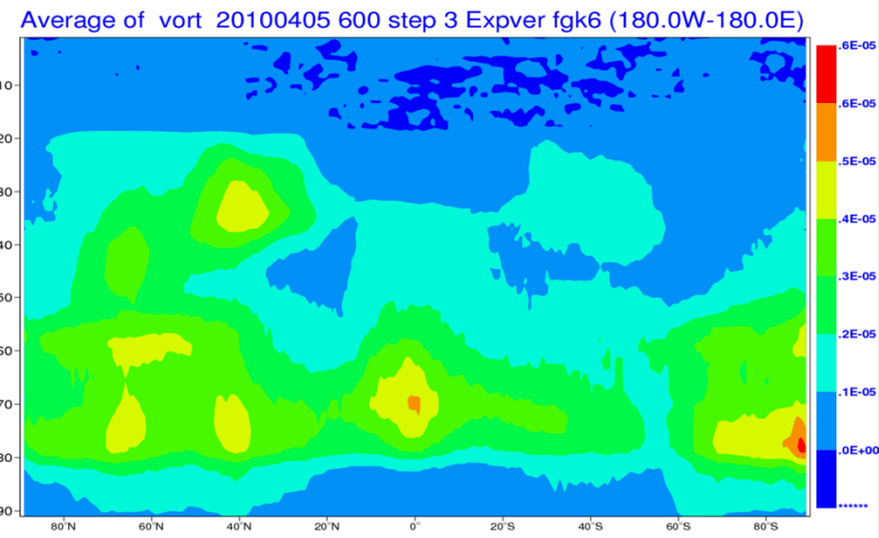
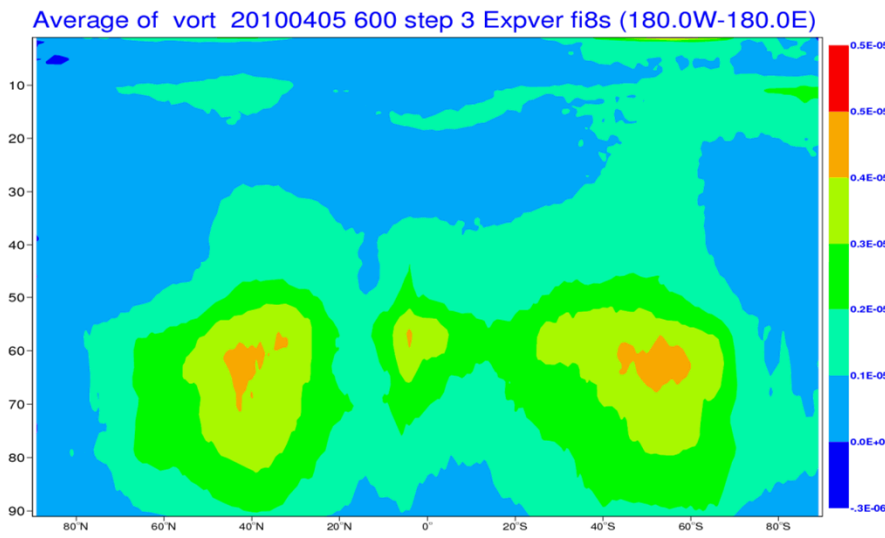
EDA Vorticity spread – no model error (fgk7)

Mean Vertical
EDA Vo spread
Cross Section



Impact of SPPT on VO spread (fi8s-fgk7)

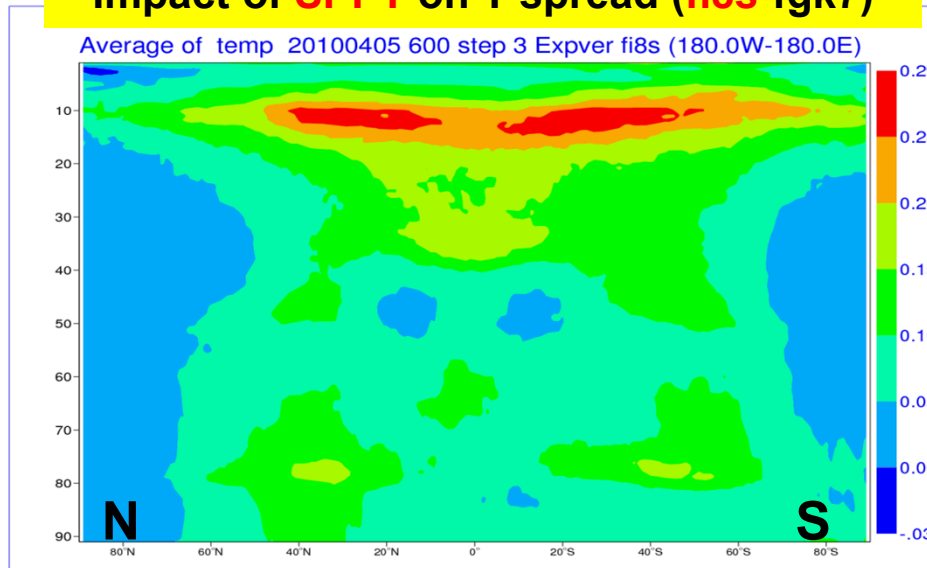
Addit. Impact of SKEB on VO spread (fgk6-fi8s)



Impact of model error parameterizations

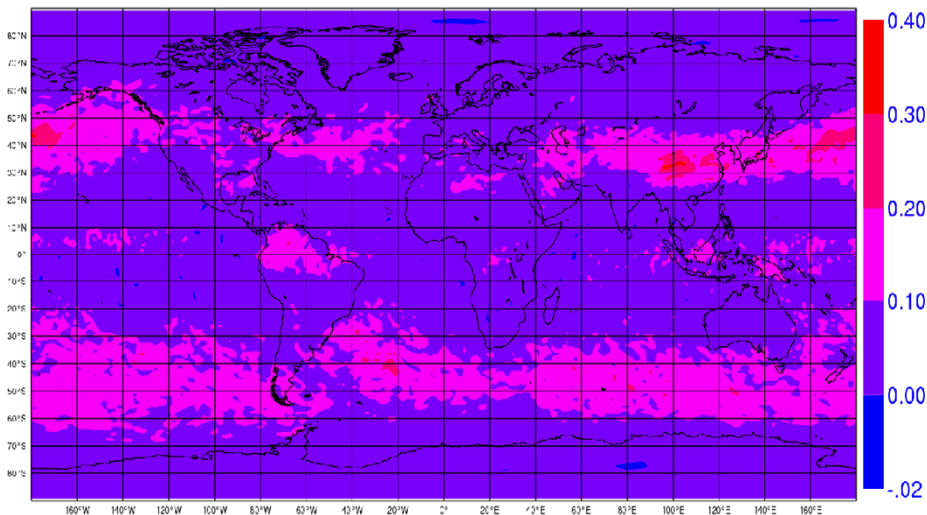
Impact of SPPT on T spread (fi8s-fgk7)

Average of temp 20100405 600 step 3 Expver fi8s (180.0W-180.0E)

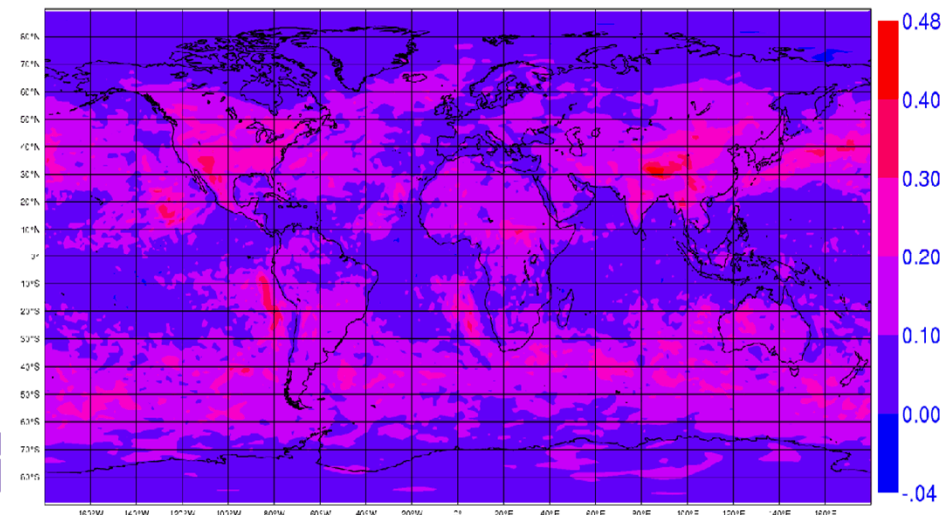


Impact of SPPT
EDA T spread

SPPT on T spread: model lev 48 (200 hPa)



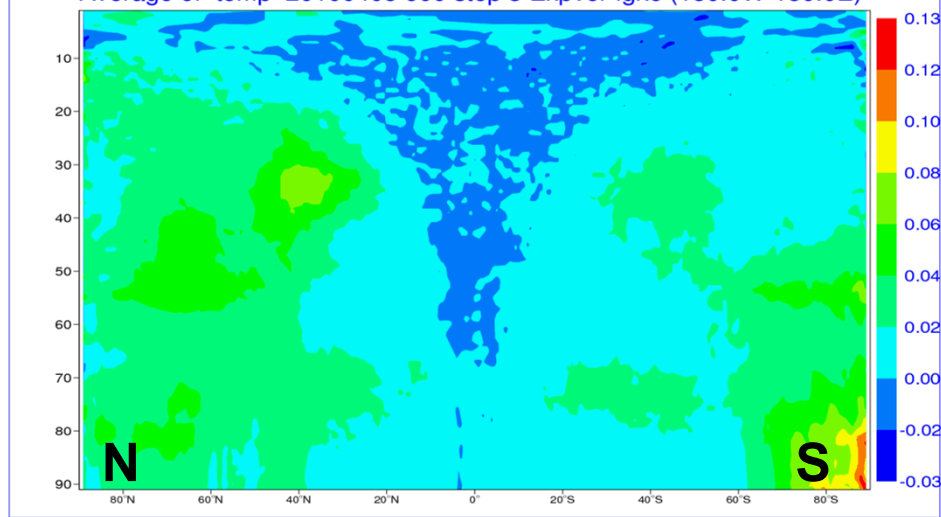
SPPT on T spread: model lev 78 (850 hPa)



Impact of model error parameterizations

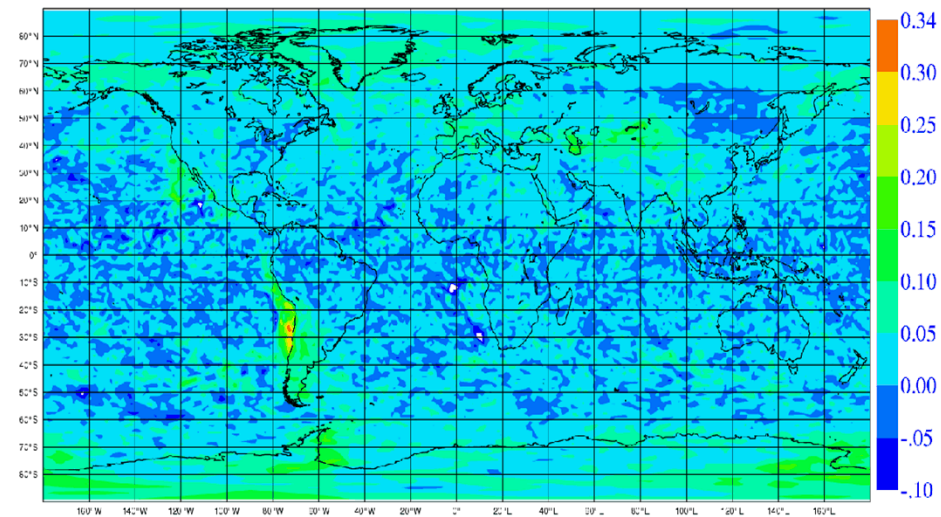
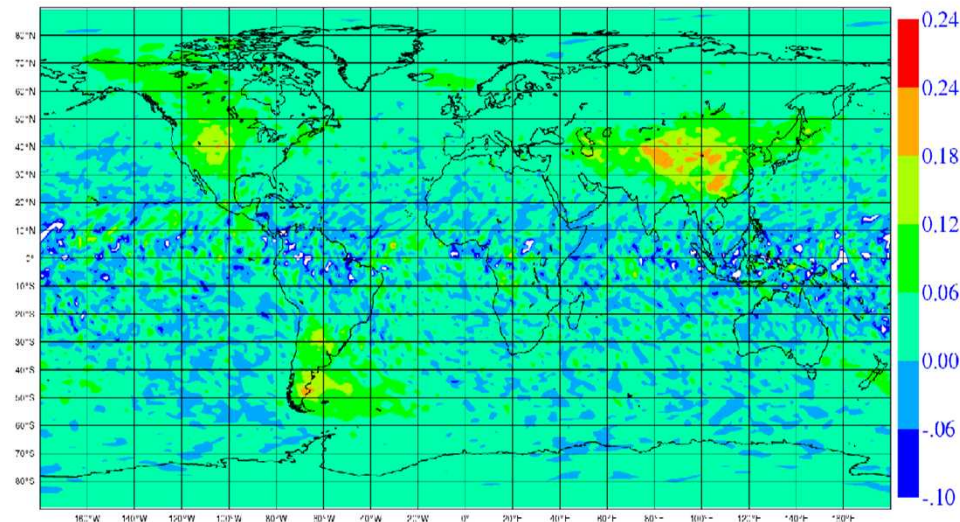
Additional Impact of SKEB on T spread (fgk6-fi8s)

Impact of SKEB
EDA T spread



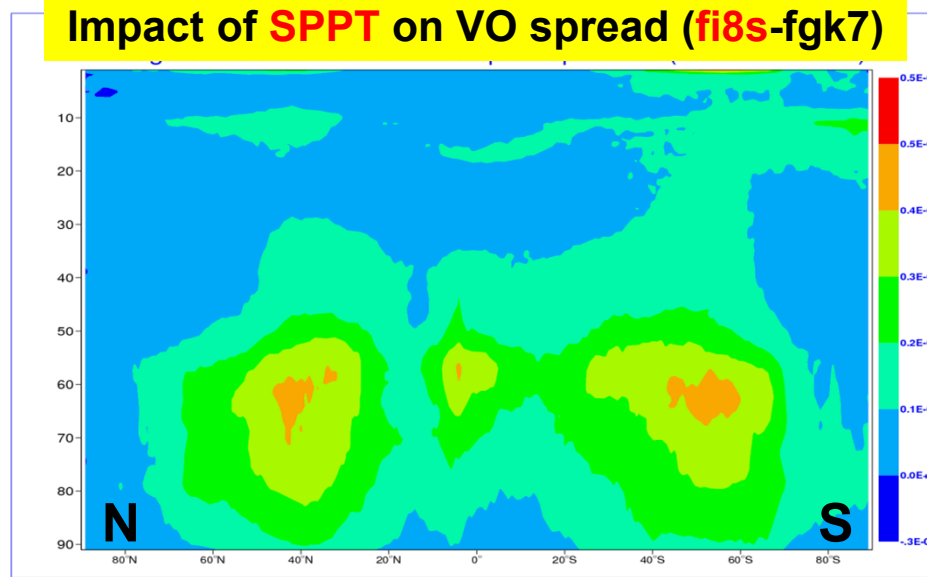
SKEB on T spread: model lev 38 (100 hPa)

SPPT on T spread: model lev 78 (850 hPa)

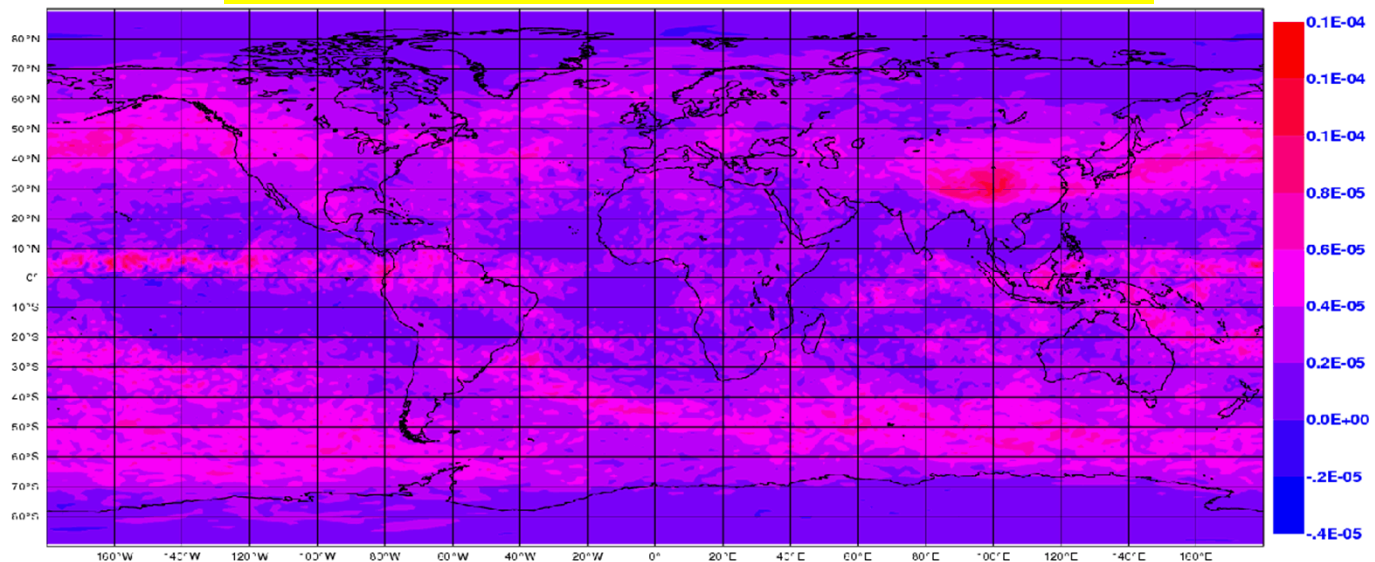


Impact of model error parameterizations

Impact of **SPPT**
EDA Vo spread



SPPT on VO spread: model lev 64 (500 hPa)



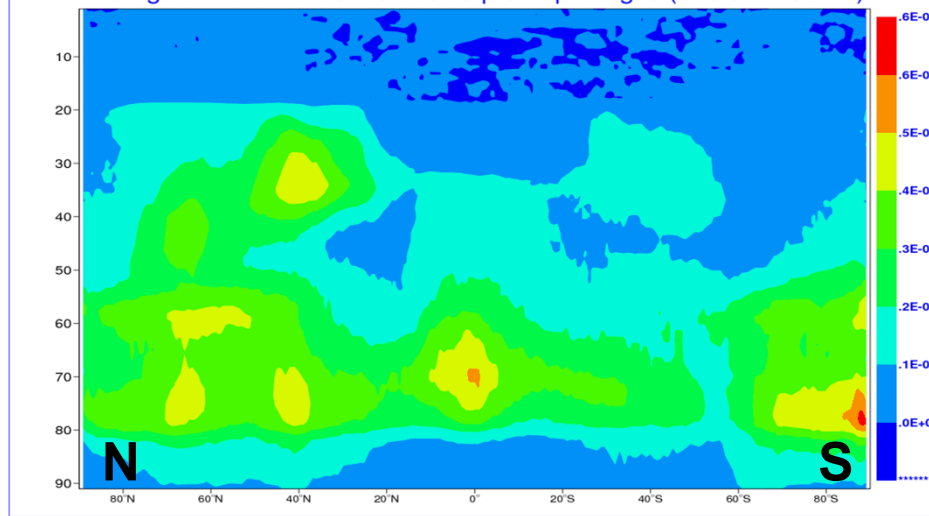
Mod



Impact of model error parameterizations

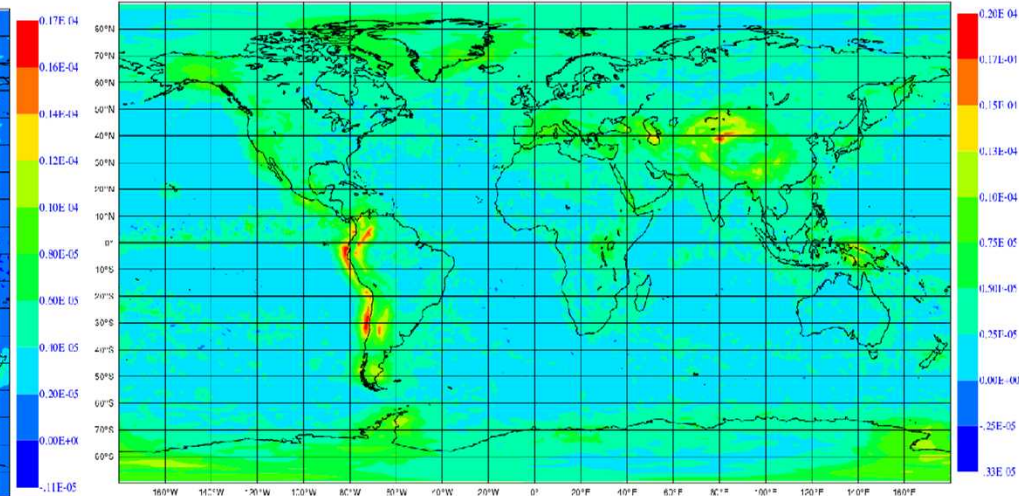
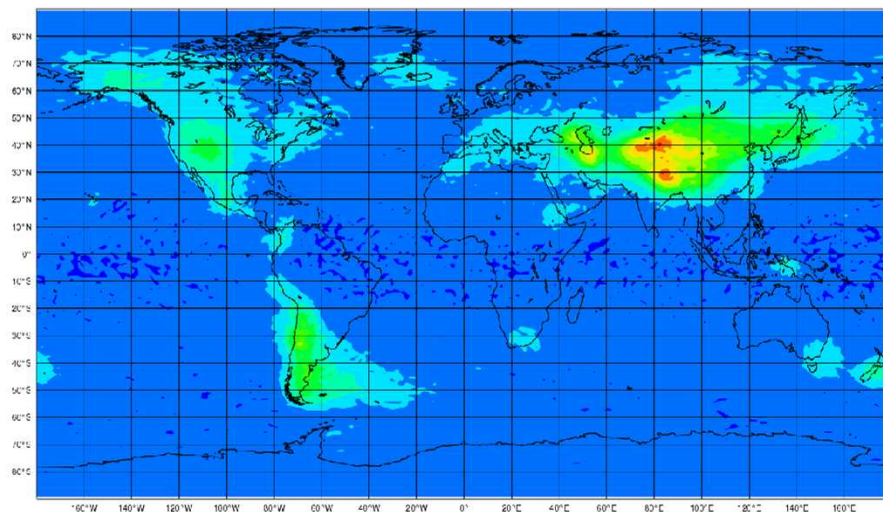
Additional Impact of SKEB on VO spread (fgk6-fi8s)

Impact of SKEB
EDA Vo spread



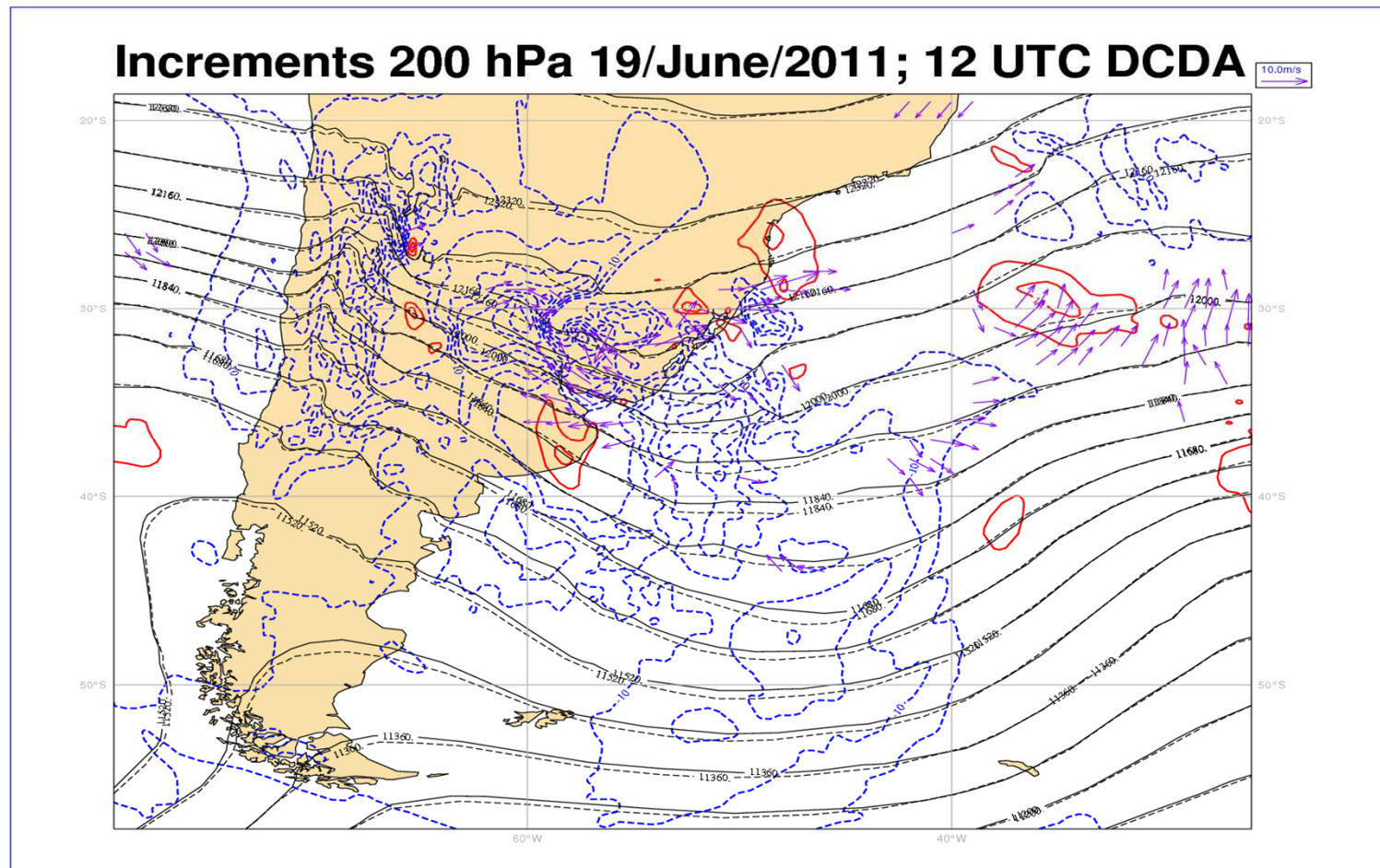
SKEB on VO spread: model lev 30 (50 hPa)

SKEB on VO spread: model lev 78 (850 hPa)



Impact of model error parameterizations

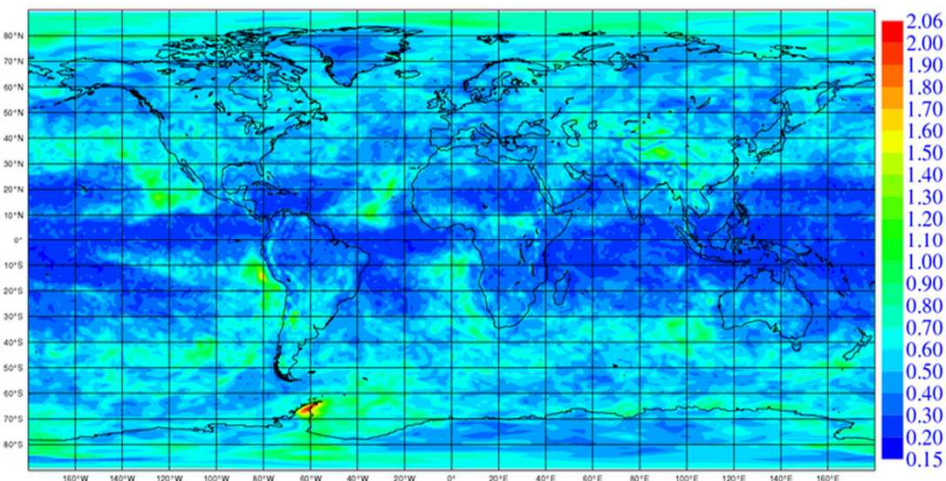
BG Errors triggered by **orographic wave activity** are seen in analysis increments maps



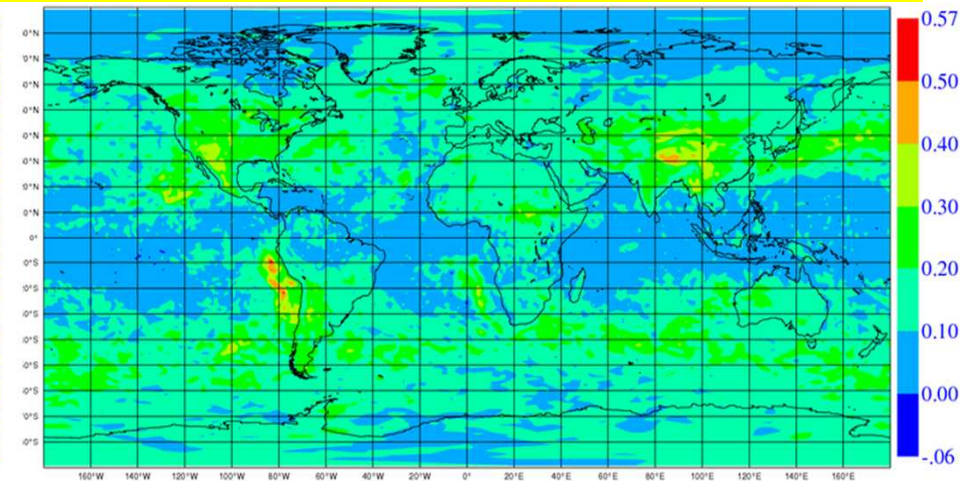
Impact of model error parameterizations

Does the use of model error param. make the **EDA spread** a “better” predictor of **background error StDev**?
(perceived background errors = control bg – operational ana)

BG Error Temperature lev 78 (850 hPa)

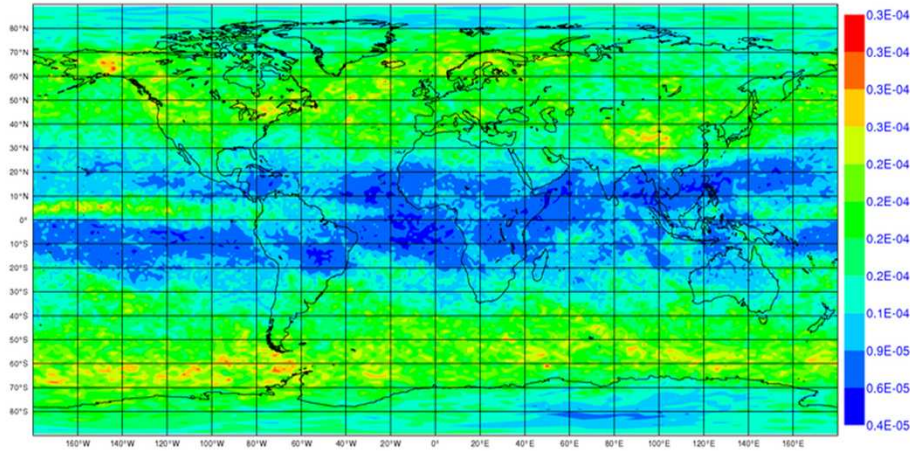


Impact of SPPT + SKEB on EDA T spread lev 78 (850 hPa)

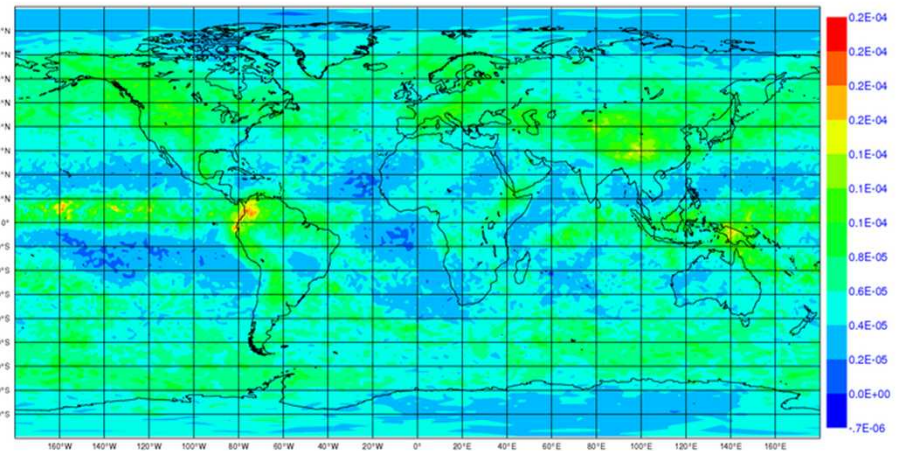


Impact of model error parameterizations

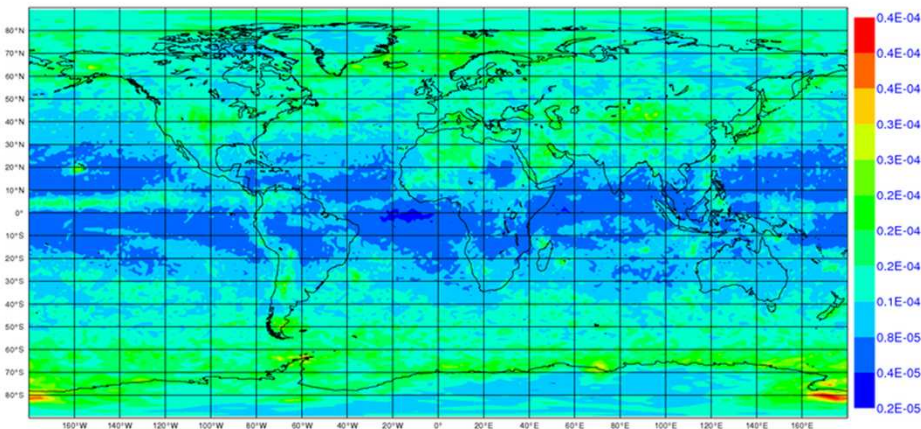
BG Error Vorticity lev 64 (500 hPa)



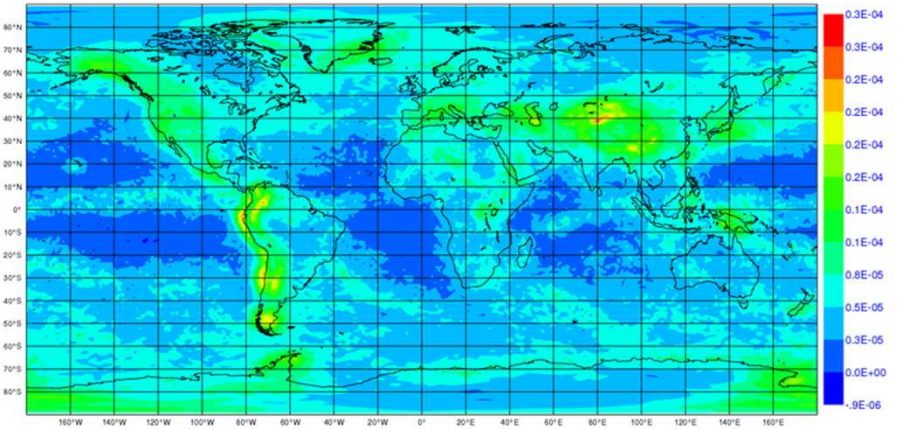
Impact of SPPT + SKEB on EDA Vo spread lev 64



BG Error Vorticity lev 78 (850 hPa)



Impact of SPPT + SKEB on EDA Vo spread lev 78



Impact of model error parameterizations

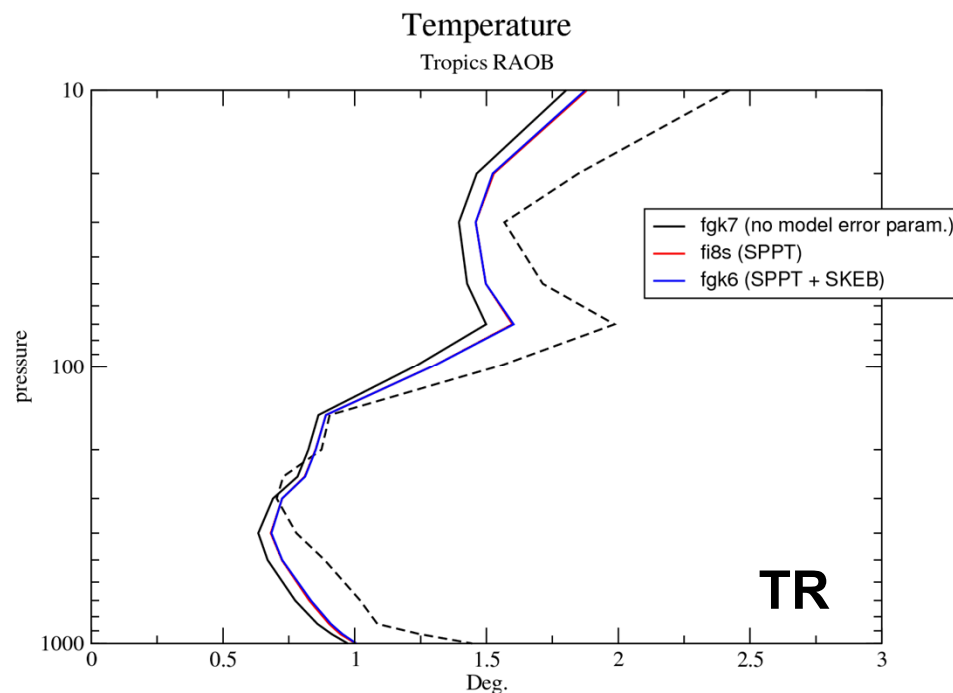
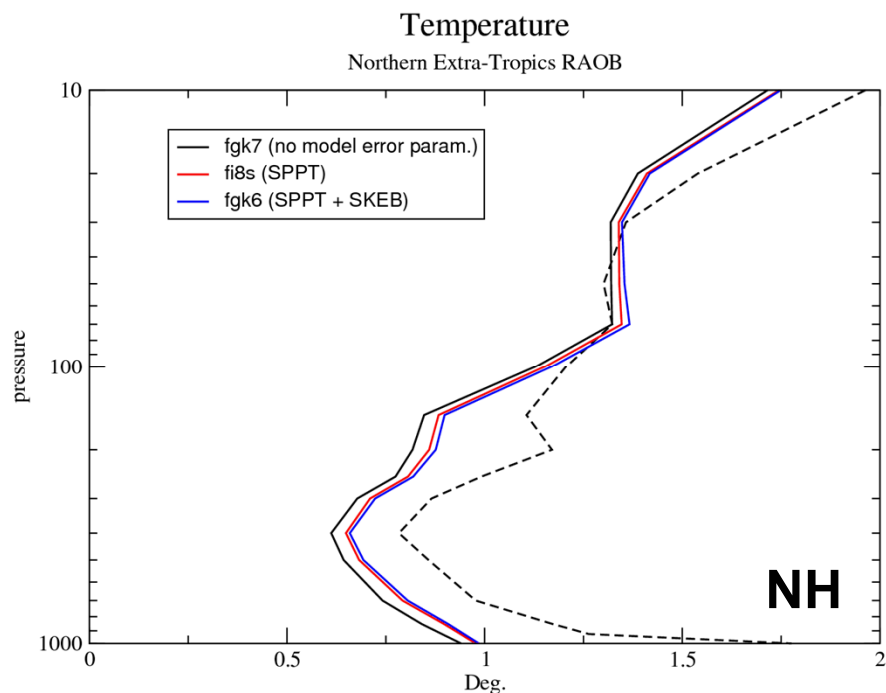
Does the use of model error param. make the **EDA spread** a “better” predictor of **background errors StDev**?

For a reliable (E)DA:

$$\begin{aligned}\langle \mathbf{d}_i \mathbf{d}_i^T \rangle &= \mathbf{H} \mathbf{B}_i \mathbf{H}^T + \mathbf{R} \\ \text{diag}(\langle \mathbf{d}_i \mathbf{d}_i^T \rangle) &= \text{diag}(\mathbf{H} \mathbf{B}_i \mathbf{H}^T) + \text{diag}(\mathbf{R})\end{aligned}\quad (1)$$

Innovation Variance = Expected Innovation Variance

Impact of model error parameterizations

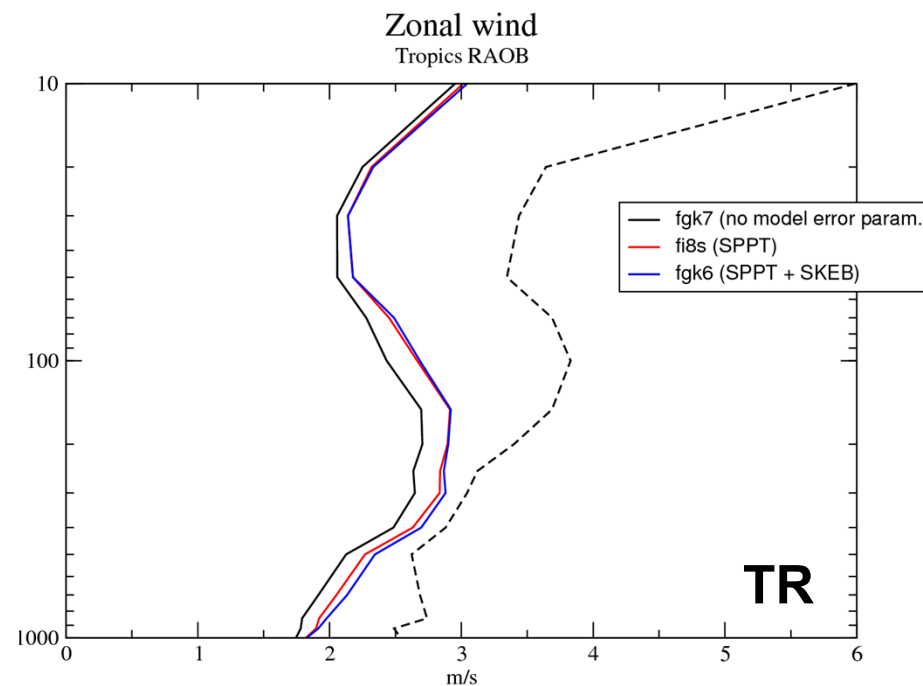
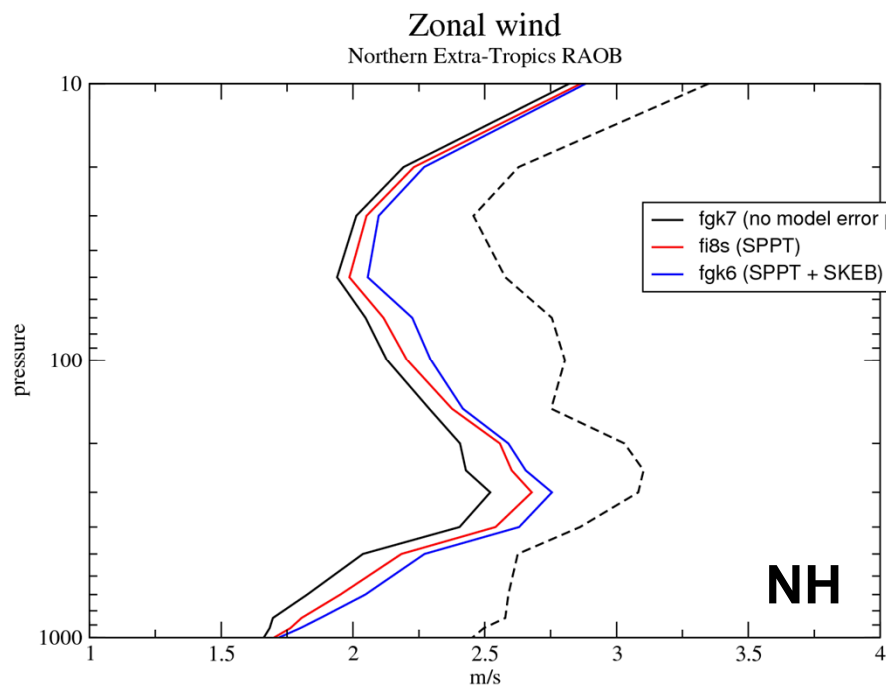


Radiosonde **temperature** obs.

Innovation StDev (dashed line)

Expected Innovation StDev (continuous line)

Impact of model error parameterizations



Radiosonde **zonal wind** obs.

Innovation StDev (dashed line)

Expected Innovation StDev (continuous line)

Impact of model error parameterizations

Does the use of model error param. make the **EDA spread** a “better” predictor of **background errors StDev**?

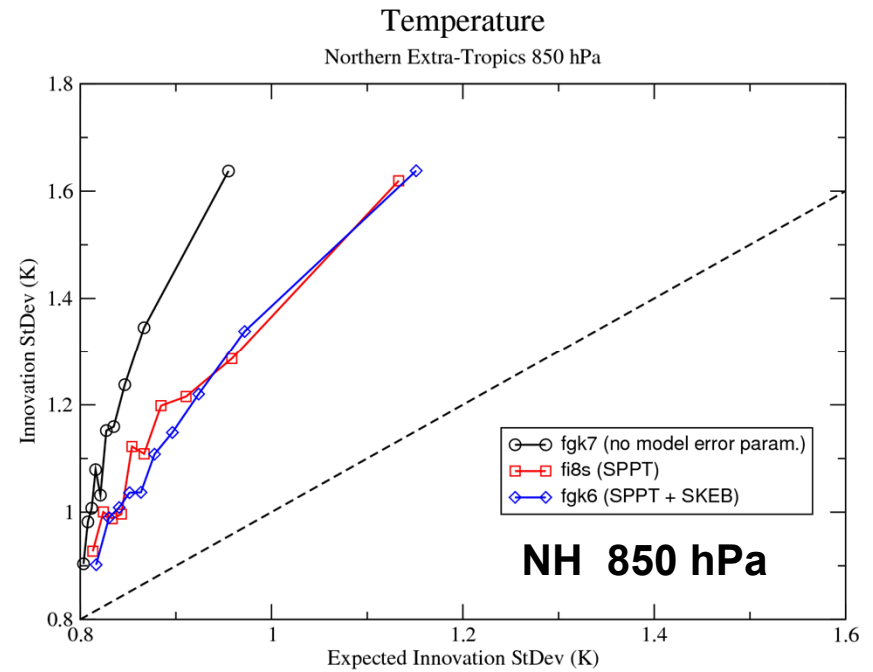
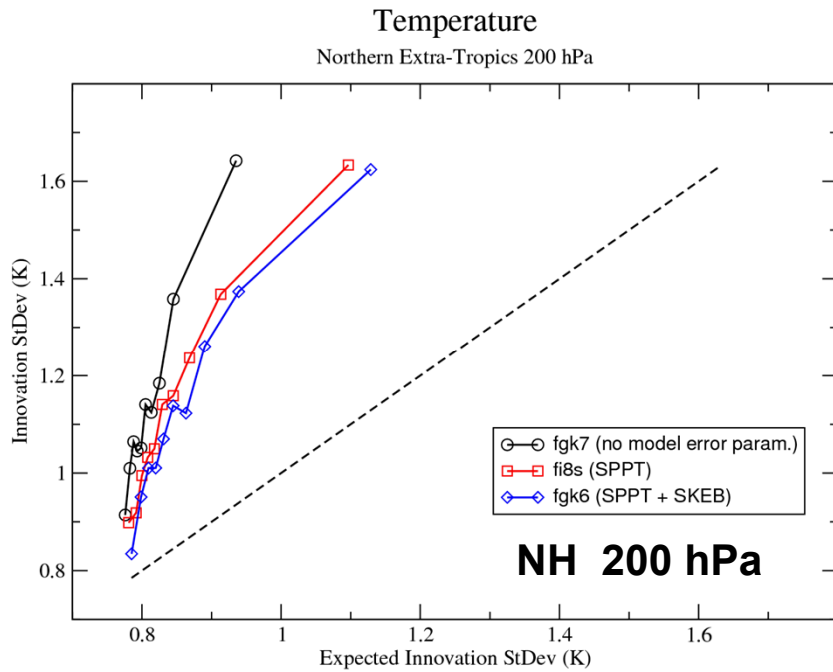
EDA spread should be a good predictor of the magnitude of background errors in a **statistical sense**: larger (smaller) EDA spread should correspond to larger (smaller) background errors, on average

We evaluate this by binning

$$diag(\langle \mathbf{d}_i \mathbf{d}_i^T \rangle) = diag(\mathbf{H} \mathbf{B}_i \mathbf{H}^T) + diag(\mathbf{R})$$

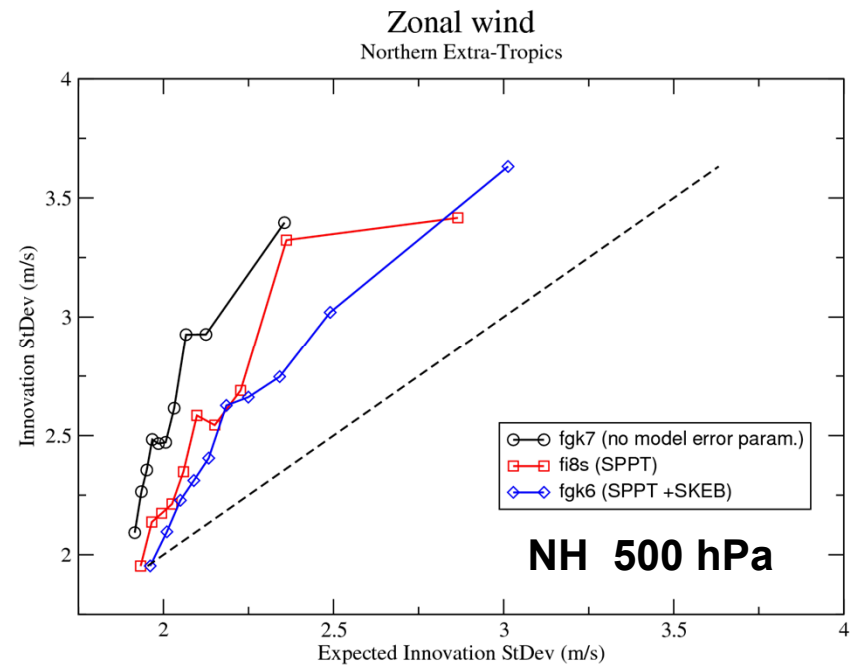
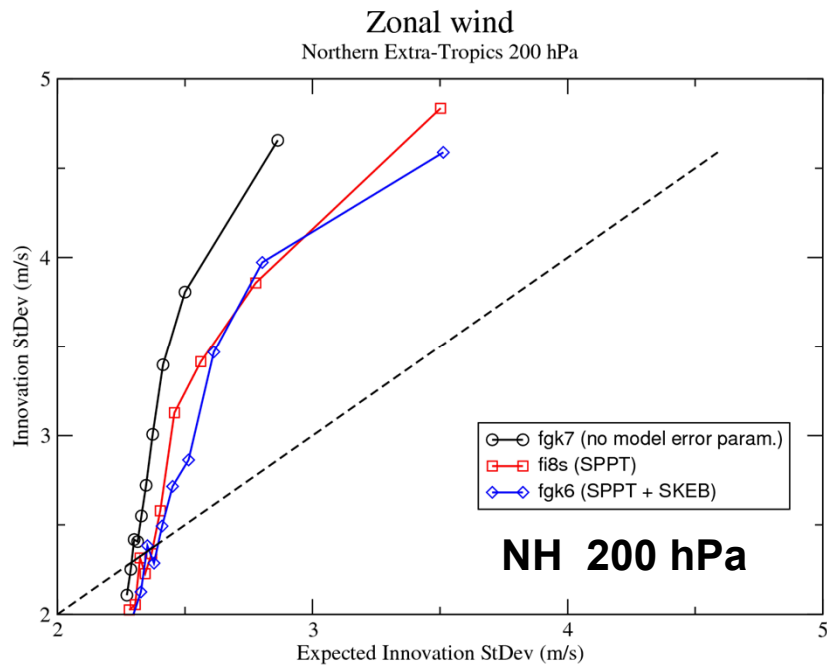
according to the magnitude of the expected innovation variance (Wang & Bishop, 2003)

Impact of model error parameterizations



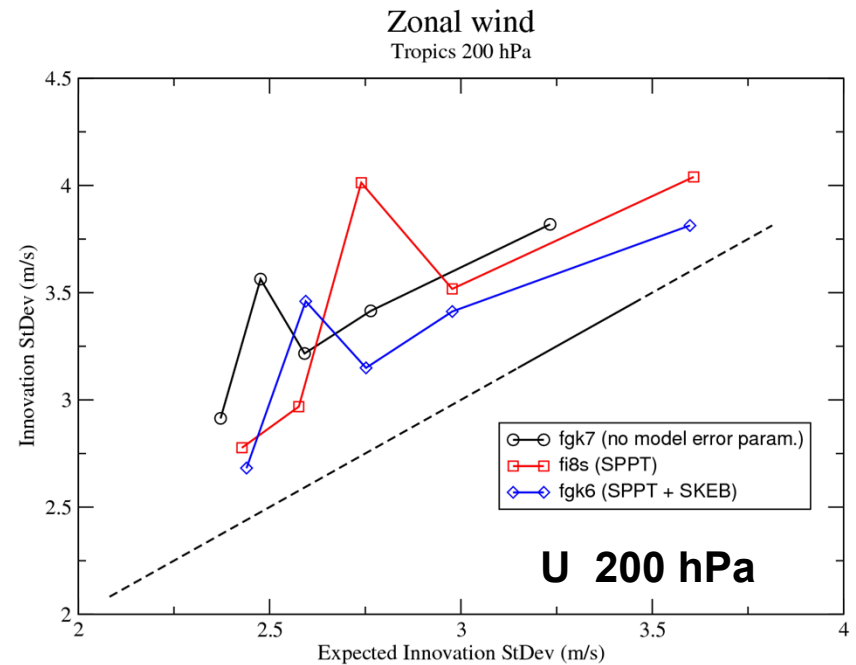
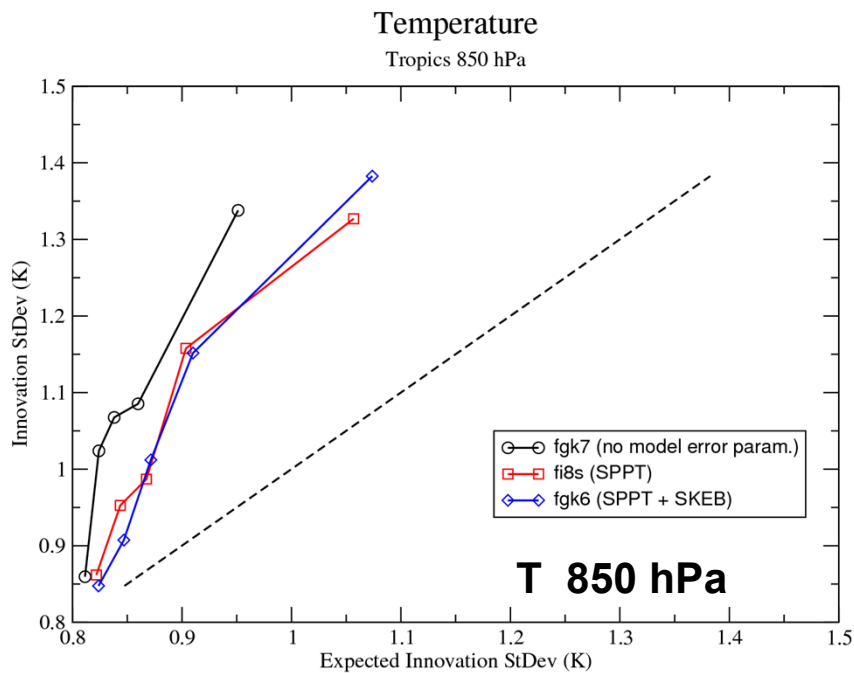
Radiosonde **temperature** obs.
Northern Extra-Tropics

Impact of model error parameterizations



Radiosonde **zonal wind** obs.
Northern Extra-Tropics

Impact of model error parameterizations

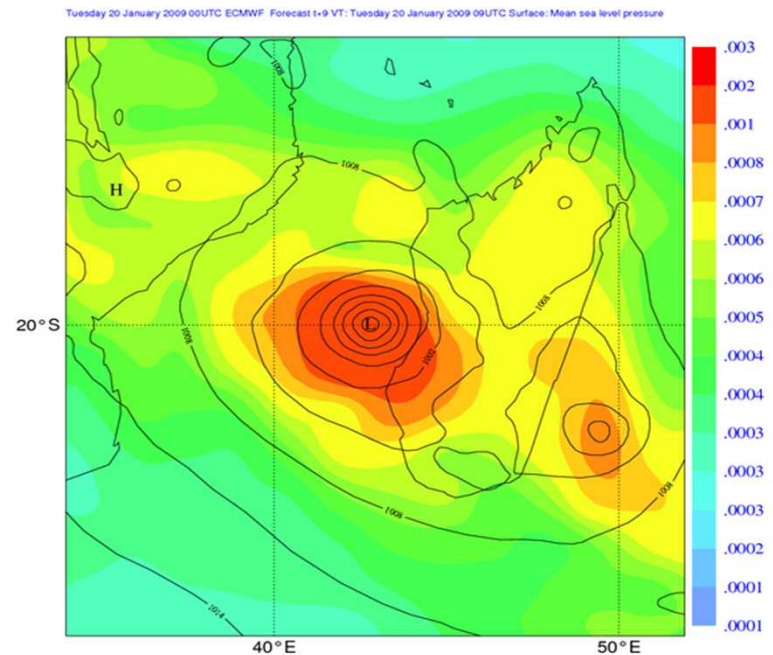


Radiosonde obs., Tropics

Impact of model error parameterizations

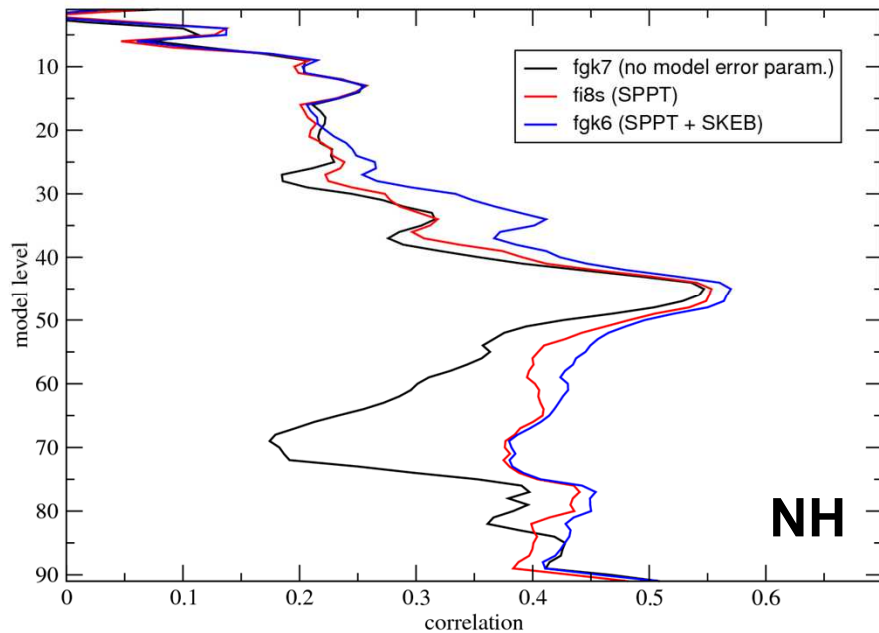
EDA spread should be able to predict the magnitude of background errors in a “**deterministic**” sense: areas where EDA spread is large (small) w.r. to its climatological mean should correspond to areas of larger (smaller) background uncertainty.

The effect of model error param. can be quantified by looking at the time averaged spatial correlation between EDA spread and perceived background errors

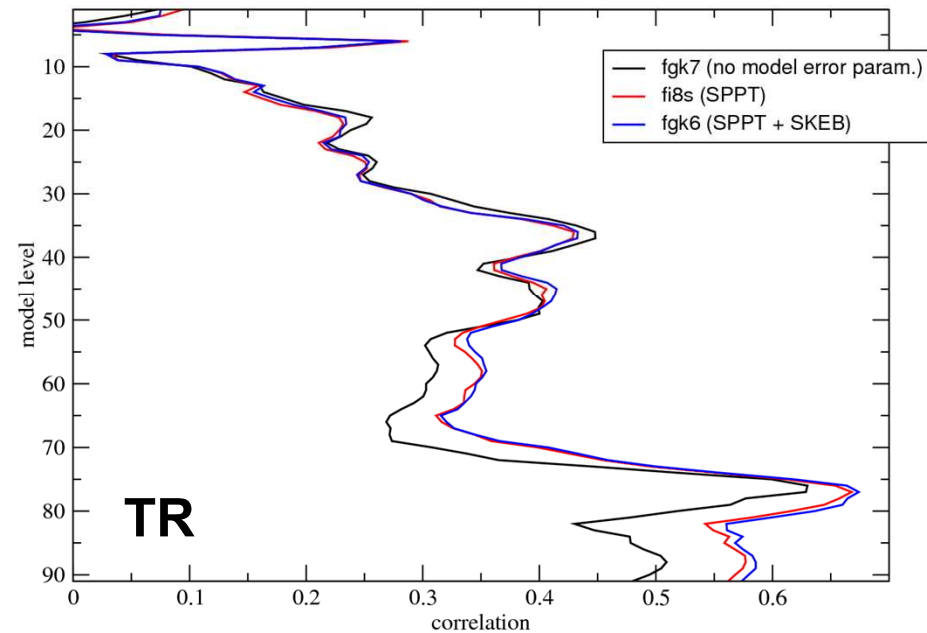


Impact of model error parameterizations

Temperature
Northern Extra Tropics

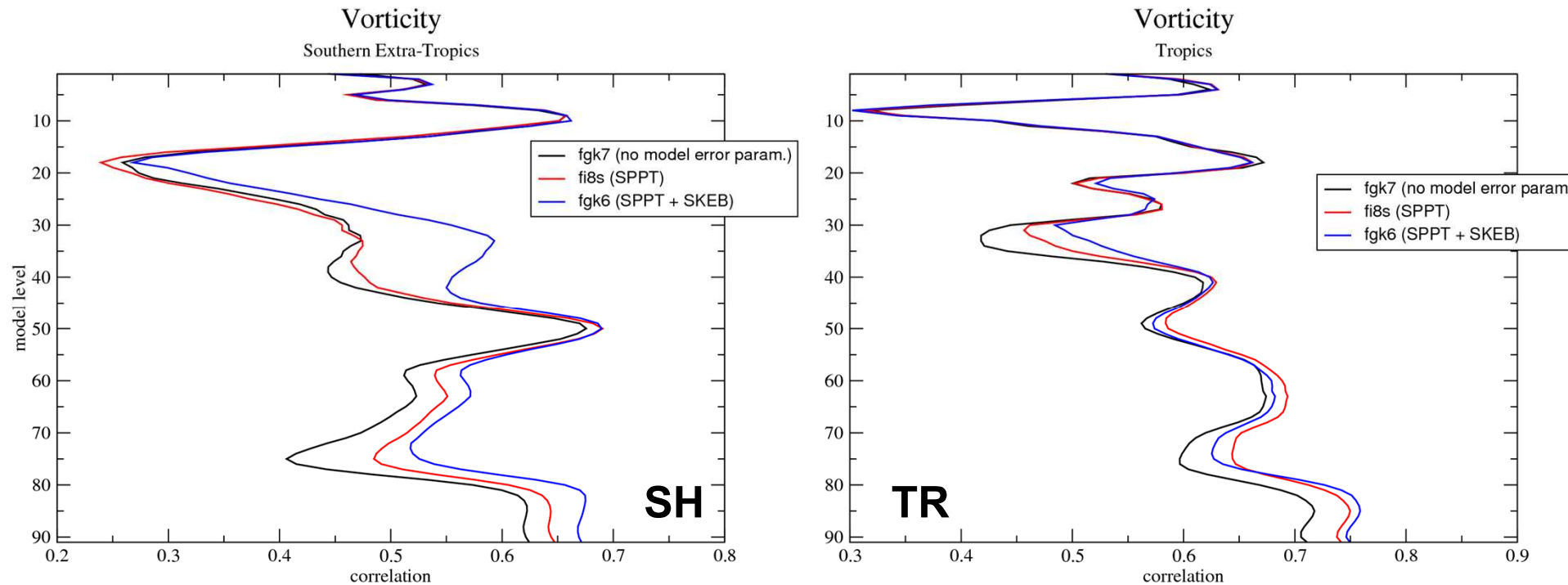


Temperature
Tropics



Time averaged spatial correlation between **temperature** EDA spread and perceived background errors

Impact of model error parameterizations



Time averaged spatial correlation between **vorticity** EDA spread and perceived background errors

Impact of model error parameterizations

EDA perturbations are also used to diagnose the **covariance** structures of background errors.

This is currently done offline to estimate a climatological **B** in 4D-Var, and it is envisaged to be done online to compute a flow-dependent **B** when a sufficiently large EDA will be available.

We would like to estimate how much the EDA perturbations project onto the background error patterns.

An approx. measure is the 'Perturbation versus Error Correlation Analysis' (**PECA**, Wei and Toth, 2003)

Impact of model error parameterizations

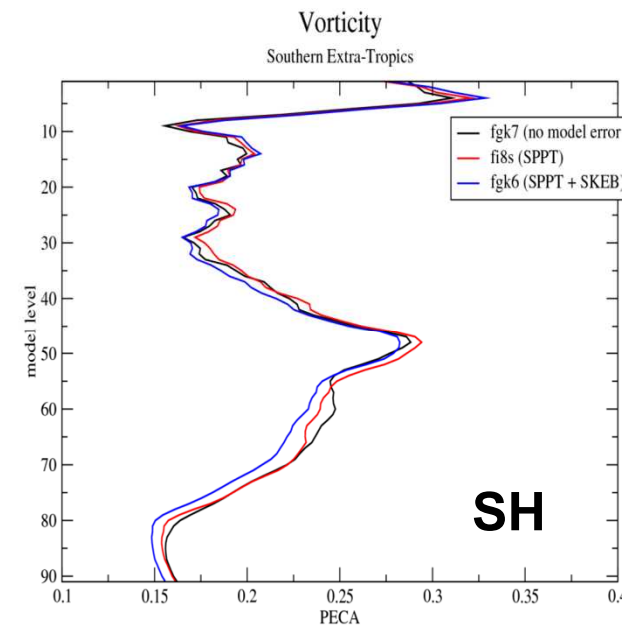
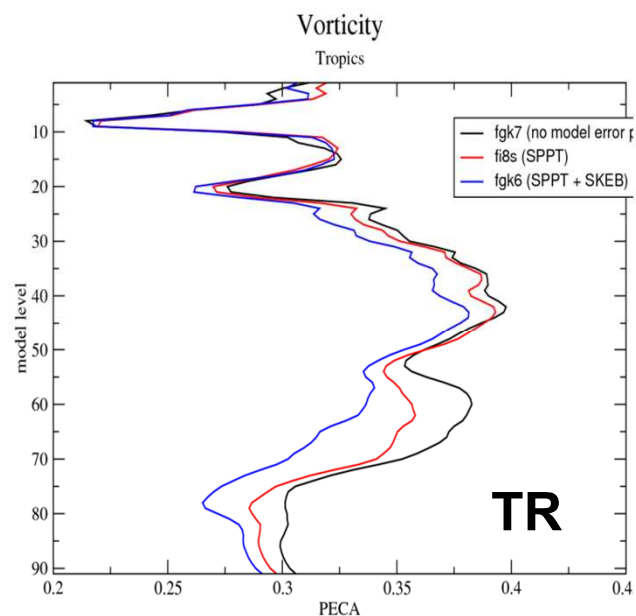
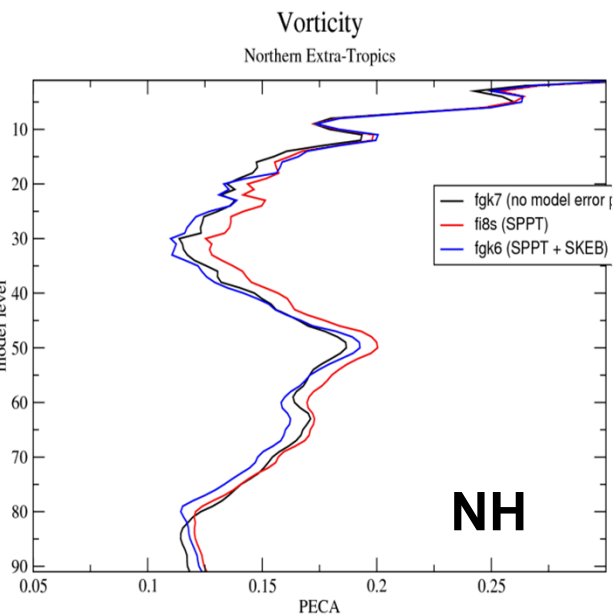
$$PECA \equiv \frac{1}{N_{ens}} \sum_{j=1}^{N_{ens}} cor(\varepsilon_b, pert_j)$$

Where ε_b = control bg - verifying analysis,
 $pert_j$ = member_j bg – control bg

What is the impact of model error parameterizations on this diagnostic?

Impact of model error parameterizations

$$PECA \equiv \frac{1}{N_{ens}} \sum_{j=1}^{N_{ens}} cor(\varepsilon_b, pert_j)$$



Should we be concerned?

Conclusions and Plans

- The EDA is arguably the best tool available to us to estimate analysis and background errors
- The EDA depends on a 'correct' specification of the sources of uncertainties: observation errors, **model errors**, boundary condition errors. This makes it a stringent test for errors parameterizations
- Model errors are represented in the EDA using physically plausible Monte Carlo realizations also used in the ECMWF EPS: **SPPT** and **SKEB**
- The use of model error parameterizations improves the **statistical reliability** of the EDA short range forecasts.

Conclusions and Plans

- EDA still underdispersive wrt radiosonde innovations (and own analysis): problems in **R** or model error tuned for EPS?
- The use of model error parameterizations improves the **spatial correlation** of the EDA spread with the ‘perceived’ background errors standard deviation
- The use of the **SKEB** param. in addition to the **SPPT** gives additional benefit, especially for the representation of wind field errors
- These positive diagnostics indications will be verified in an assimilation experiment using errors from an EDA with same model error parameterizations as in EPS

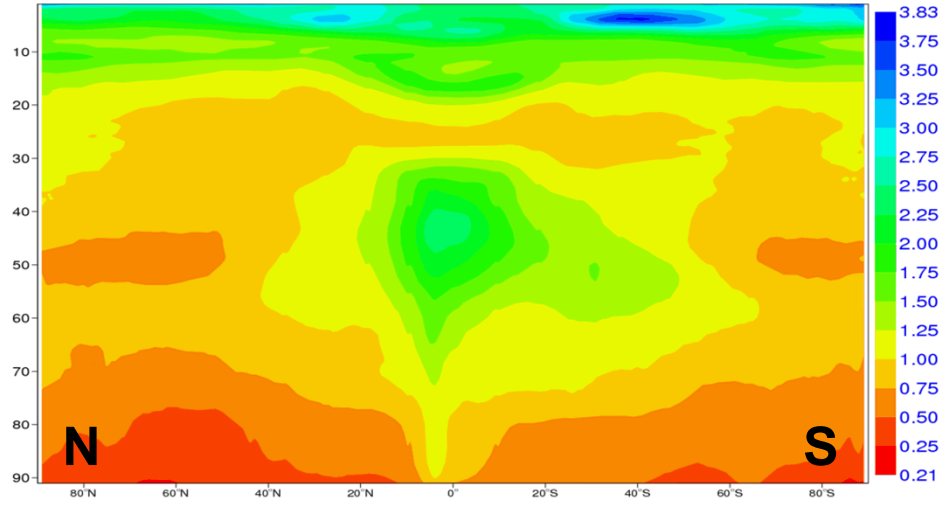
Conclusions and Plans

- The impact of current model error param. (especially SKEB) on the EDA ability to simulate bg error **covariances** needs further investigation: assimilation experiments using climatological **B** statistics derived from EDA with different model errors are required

Impact of model error parameterizations

EDA U wind spread – no model error (fgk7)

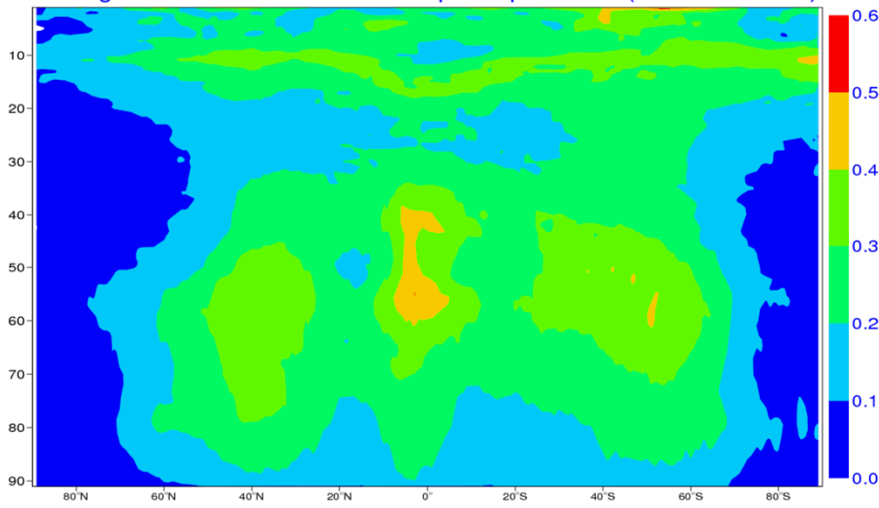
Average of u-vel 20100405 600 step 3 Expver FGK7 (180.0W-180.0E)



Mean Vertical
EDA U spread
Cross Section

Impact of SPPT on U spread (fi8s-fgk7)

Average of u-vel 20100405 600 step 3 Expver F18S (180.0W-180.0E)



Addit. Impact of SKEB on U spread (fgk6-fi8s)

Average of u-vel 20100405 600 step 3 Expver FGK6 (180.0W-180.0E)

